IPB120N06S4-03 IPI120N06S4-03, IPP120N06S4-03

| Parameter | Symbol | Conditions | Values | | | Unit |
|------------------------------------------------|---------------------|----------------------------------------------|--------|------|------|------|
| | | | min. | typ. | max. | |
| Thermal characteristics ²⁾ | | | | | | |
| Thermal resistance, junction - case | R _{thJC} | - | - | - | 0.9 | K/W |
| Thermal resistance, junction - ambient, leaded | R_{thJA} | - | - | - | 62 | |
| SMD version, device on PCB | R_{thJA} | minimal footprint | - | - | 62 | |
| | | 6 cm ² cooling area ³⁾ | - | = | 40 | |

Electrical characteristics, at $T_{\rm j}$ =25 °C, unless otherwise specified

Static characteristics

| Drain-source breakdown voltage | V _{(BR)DSS} | $V_{\rm GS}$ =0V, $I_{\rm D}$ = 1mA | 60 | - | - | V |
|----------------------------------|----------------------|-----------------------------------------------------------------------|-----|------|-----|----|
| Gate threshold voltage | $V_{\rm GS(th)}$ | $V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 120 \mu {\rm A}$ | 2.0 | 3.0 | 4.0 | |
| Zero gate voltage drain current | I _{DSS} | V _{DS} =60V, V _{GS} =0V, T _j =25°C | - | 0.01 | 1 | μΑ |
| | | $V_{\rm DS}$ =60V, $V_{\rm GS}$ =0V, $T_{\rm j}$ =125°C ²⁾ | - | 10 | 200 | |
| Gate-source leakage current | I _{GSS} | V _{GS} =20V, V _{DS} =0V | - | - | 100 | nA |
| Drain-source on-state resistance | R _{DS(on)} | V _{GS} =10V, I _D =100A | - | 2.6 | 3.2 | mΩ |
| | | V _{GS} =10V, I _D =100A, SMD version | - | 2.3 | 2.8 | |



| Parameter | Symbol Conditions | Conditions | Values | | | Unit |
|-----------------------------------------------|----------------------|------------------------------------------------------------------------------------|--------|-------|-------|------|
| | | | min. | typ. | max. | |
| Dynamic characteristics ²⁾ | | | | | | |
| Input capacitance | C iss | V _{GS} =0V, V _{DS} =25V, f=1MHz | - | 10120 | 13150 | pF |
| Output capacitance | C _{oss} | | - | 2480 | 3220 | |
| Reverse transfer capacitance | C _{rss} | | - | 100 | 200 | |
| Turn-on delay time | $t_{d(on)}$ | $V_{\rm DD}$ =30V, $V_{\rm GS}$ =10V, $I_{\rm D}$ =120A, $R_{\rm G}$ =3.5 Ω | - | 40 | - | ns |
| Rise time | t _r | | - | 10 | - | |
| Turn-off delay time | $t_{\text{d(off)}}$ | | - | 80 | - | |
| Fall time | t _f | | - | 15 | - | |
| Gate Charge Characteristics ²⁾ | | | | | | |
| Gate to source charge | Q _{gs} | | - | 54 | 70 | nC |
| Gate to drain charge | Q_{gd} | $V_{\rm DD}$ =48V, $I_{\rm D}$ =120A, $V_{\rm GS}$ =0 to 10V | - | 13.5 | 27 | |
| Gate charge total | Q _g | | - | 125 | 160 | |
| Gate plateau voltage | $V_{\rm plateau}$ | | - | 5.3 | ı | V |
| Reverse Diode | | | | | | |
| Diode continous forward current ²⁾ | Is | - T _C =25°C | - | - | 120 | А |
| Diode pulse current ²⁾ | I _{S,pulse} | | - | - | 480 | |
| Diode forward voltage | V _{SD} | V _{GS} =0V, I _F =100A, T _j =25°C | 0.6 | 0.95 | 1.3 | V |
| Reverse recovery time ²⁾ | t _{rr} | V_R =30V, I_F =120A, d i_F /d t =100A/µs | - | 115 | - | ns |
| Reverse recovery charge ²⁾ | Q _{rr} | 1 | - | 110 | - | nC |

¹⁾ Current is limited by bondwire; with an $R_{\rm thJC}$ = 0.9K/W the chip is able to carry 181A at 25°C.

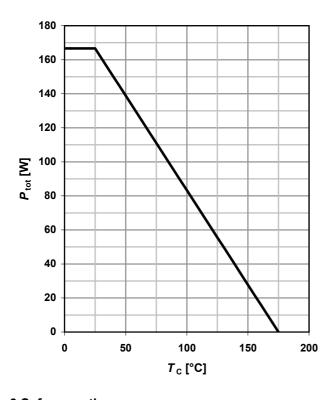
²⁾ Specified by design. Not subject to production test.

 $^{^{3)}}$ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm 2 (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical in still air.



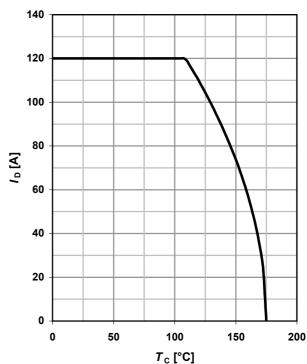
1 Power dissipation

$$P_{\text{tot}} = f(T_{\text{C}}); V_{\text{GS}} \ge 6 \text{ V}$$



2 Drain current

$$I_D = f(T_C); V_{GS} \ge 6 \text{ V}; SMD$$



3 Safe operating area

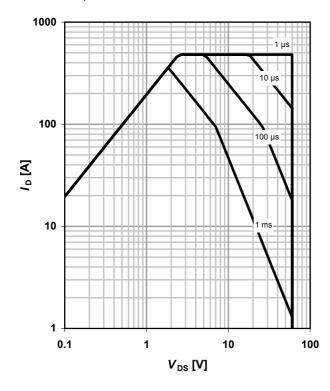
$$I_D = f(V_{DS}); T_C = 25 \,^{\circ}\text{C}; D = 0; \text{SMD}$$

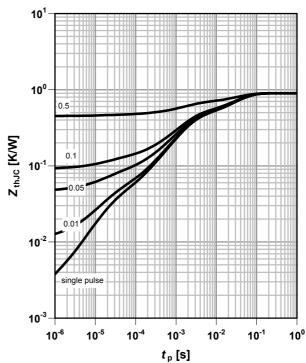
parameter: t_p

4 Max. transient thermal impedance

$$Z_{\rm thJC} = f(t_{\rm p})$$

parameter: $D = t_p/T$



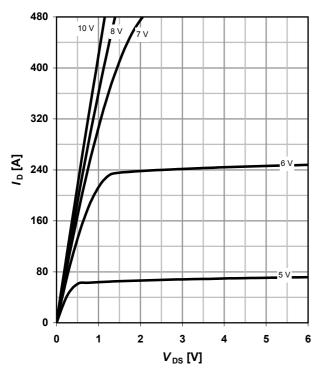




5 Typ. output characteristics

 $I_D = f(V_{DS}); T_j = 25 °C; SMD$

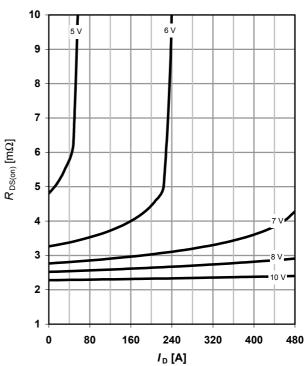
parameter: V_{GS}



6 Typ. drain-source on-state resistance

 $R_{DS(on)} = f(I_D); T_j = 25 \text{ °C}; SMD$

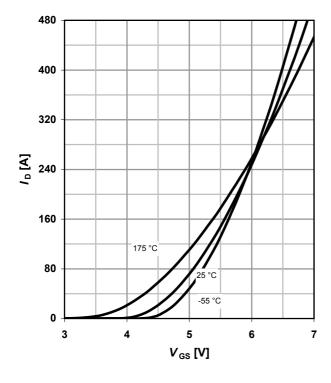
parameter: V_{GS}



7 Typ. transfer characteristics

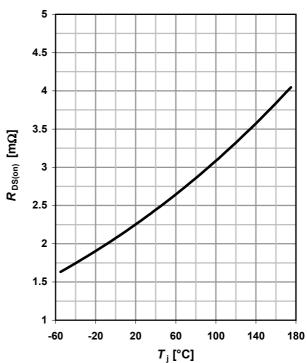
 $I_D = f(V_{GS}); V_{DS} = 6V$

parameter: T_i



8 Typ. drain-source on-state resistance

$$R_{DS(on)} = f(T_j); I_D = 100 \text{ A}; V_{GS} = 10 \text{ V}; \text{SMD}$$





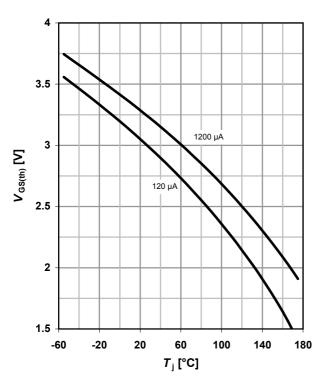
9 Typ. gate threshold voltage

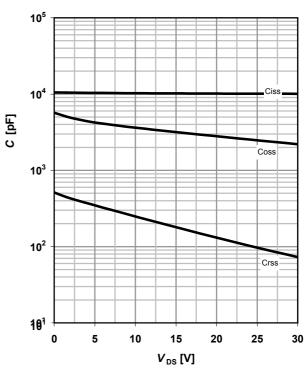
 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$

parameter: I_D

10 Typ. capacitances

$$C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$$





11 Typical forward diode characteristicis

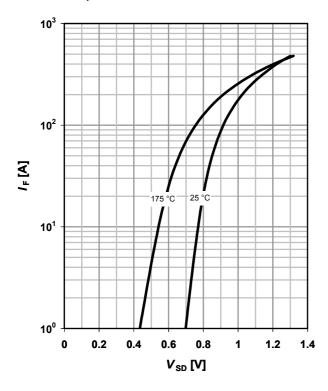
 $IF = f(V_{SD})$

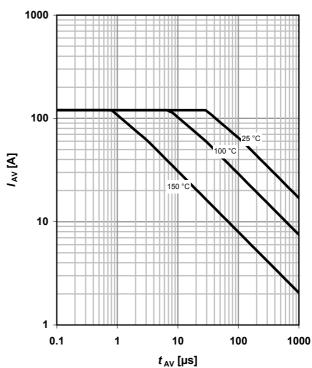
parameter: T_i

12 Avalanche characteristics

 $I_{AS} = f(t_{AV})$

parameter: T_{j(start)}





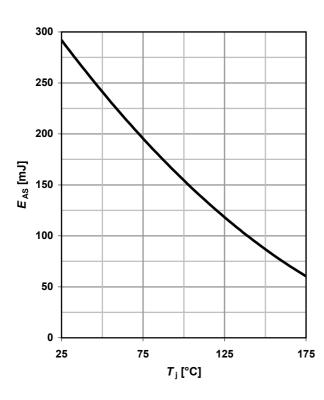


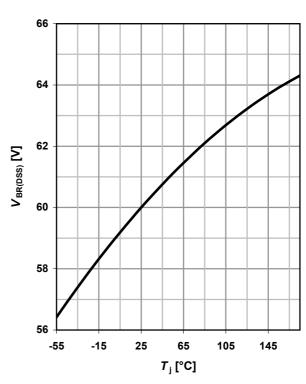
13 Avalanche energy

$$E_{AS} = f(T_i); ; I_D = 60 A$$

14 Drain-source breakdown voltage

$$V_{BR(DSS)} = f(T_j); I_D = 1 \text{ mA}$$

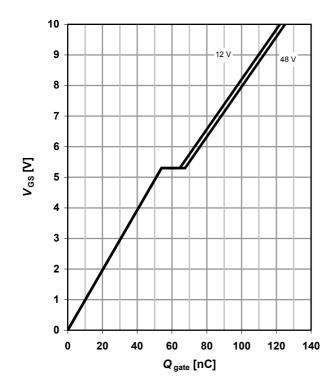




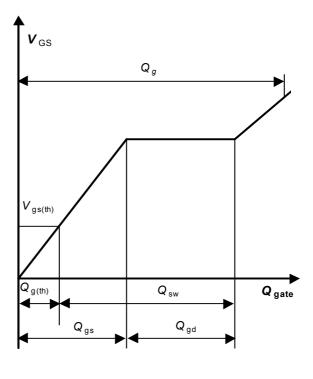
15 Typ. gate charge

 $V_{\rm GS}$ = f(Q $_{\rm gate}$); $I_{\rm D}$ = 120 A pulsed

parameter: $V_{\rm DD}$



16 Gate charge waveforms





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Revision History

| Version | Date | Changes | | |
|--------------|------------|------------------|--|--|
| Revision 1.0 | 23.03.2009 | Final data sheet | | |